

In-Line D.C. Testing of Multiple Memory Modules in a Panel Before Panel Separation

Abstract

A production test machine pre-screens panels of memory modules for shorts and leakage and other D.C. parameters. Memory modules are constructed as part of a panel of 6 or so modules formed on the same substrate. The modules are connected together by links of the substrate. The D.C. tests are performed on memory modules before separation from the panel (de-panelization), while the modules are still connected together by the panel links. Using parallel testing, a whole panel of modules can be D.C. tested at the same time. Failing modules can then be marked or noted, and the good modules separated from the panel links and sent to a more expensive A.C. tester for functional testing. The spacing or pitch of test heads on the D.C. tester can be adjusted for different sizes of panels.